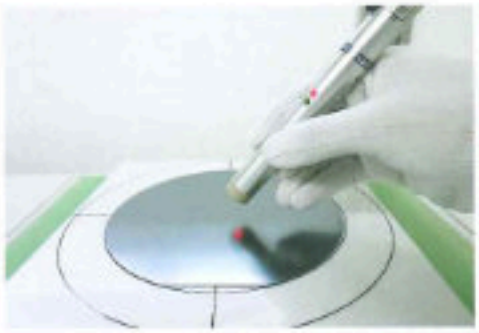
PN type checker

PN-8LP Portable pen-type non-contact PN checker





Selling Points

Principle: Photovoltaic effect with the 650nm laser diode
Power supply : DC1.5V(size AA alkaline battery), 300mA
Display of judgement : P(red) or N(green) LED lamps

Details

Applications
Semiconductor materials, Solar-cell materials (Silicon, Polysilicon, SiC etc)

Sample sizes
*Possible size to laser measurement

Measuring range
PN Checking range in resistivity : 0.02~5,000Ω·cm



PN-12α·PN-50α PN type checker ; Contact type(PN-12α) & Non-contact type(PN-50α)

PN-12α



PN-50α



Selling Points

Principle: Thermo-electromotive force(seebek effect)
Possible to check most figure of sample such as single crystalline silicon wafer, bulk, ingot and so on
*Please select from 2 types;
1) 2 probe ver.(Hot probe, Cold probe),
2) 1 probe ver.(Hot & Cold probe)

Details

Sample sizes
more than 2 inch

Measuring range
PN Checking range in resistivity : 1m ~ 20k Ω·cm
*Polycrystalline silicon, thin film on wafer, Multi/Oxidized film on wafer surface are can not judgement



Selling Points

Principle: Photovoltaic effect by light pulse irradiation
No damage and no stain by Non-contact method
Possible to check even oxidized film on wafer surface
Instantly discrimination by optical pulse illuminate

Details

Sample sizes
more than 30x30mm

Measuring range
PN Checking range in resistivity : 0.1~1,000Ω·cm



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